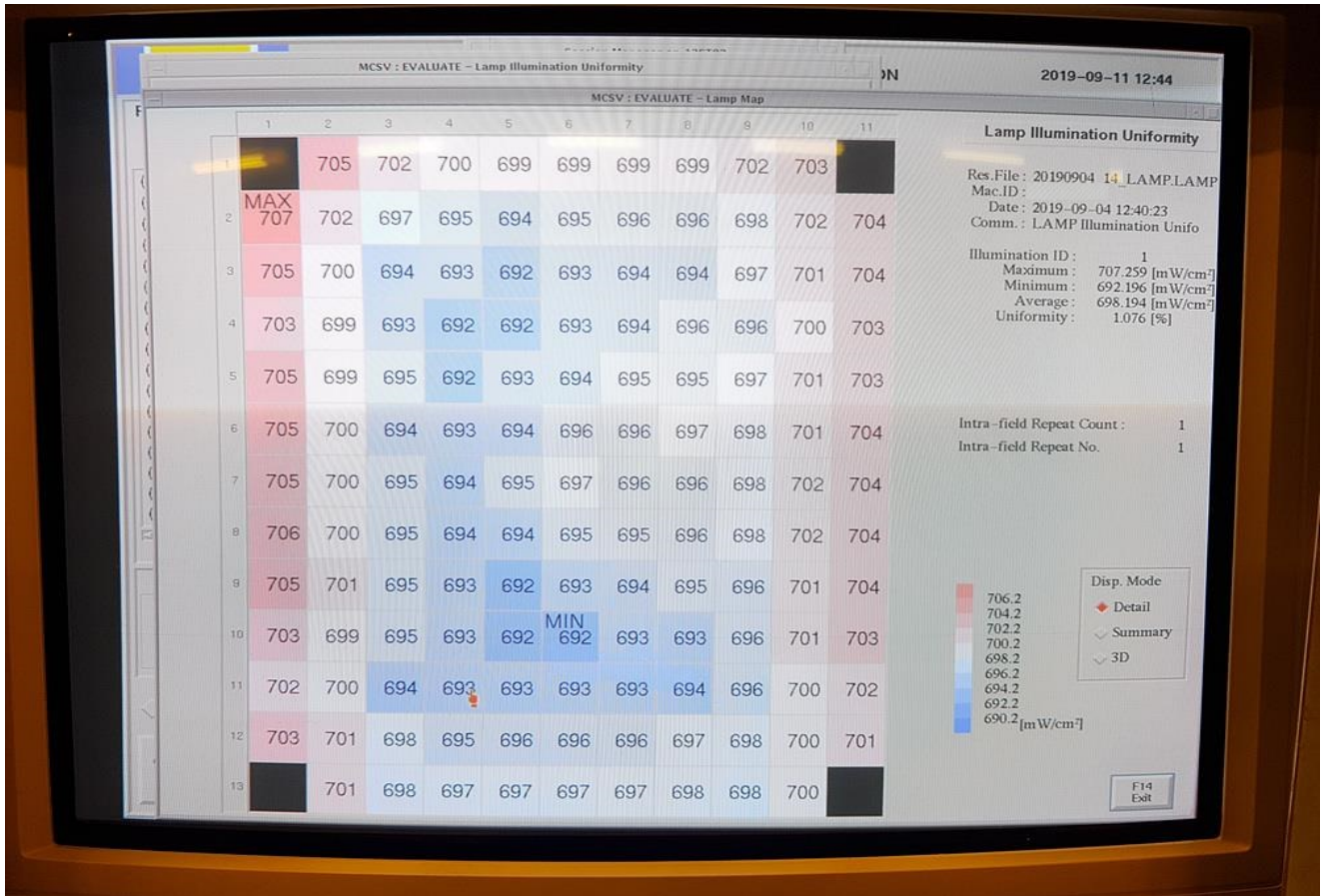


## 2205i12D Data Result

No.	Item	Spec	Data Result		Remark
1	Lamp Power	$\leq 1.5\%$	Uniformity	1.076%	
		$\geq 600 \text{ mW/cm}^2$	Lamp power	698.194 $\text{mW/cm}^2$	
2	Dose accuracy	$\leq \pm 1\%$	50mj/100mj/200mj	within 0.05%	
3	Reticle blind	0.4mm~0.8mm	Accuracy	0.5mm~0.8mm	
4	Reticle Rotation	$M + 3\sigma \leq 0.02\mu\text{m}$	absolutevalue	0.018 $\mu\text{m}$	
5	Distortion	$\leq \pm 0.5 \mu\text{m}$	X (max)	0.15 $\mu\text{m}$	
			Y (max)	0.35 $\mu\text{m}$	
			X (min)	-0.17 $\mu\text{m}$	
			Y (min)	-0.17 $\mu\text{m}$	
6	Inclination	$\leq 0.35\mu\text{m}$	Max-Min	0.131 $\mu\text{m}$	
		$\leq 0.25\mu\text{m}$	UR-LL	0.082 $\mu\text{m}$	
		$\leq 0.25\mu\text{m}$	UL-LR	0.015 $\mu\text{m}$	
7	Stepping	$\leq 0.045\mu\text{m}$	X (3 $\sigma$ )	0.028 $\mu\text{m}$	
			Y (3 $\sigma$ )	0.019 $\mu\text{m}$	
8	Overlay LSA	$\leq 0.075\mu\text{m}$	X:   M   + 3 $\sigma$	0.028 $\mu\text{m}$	
		$\leq 0.075\mu\text{m}$	Y:   M   + 3 $\sigma$	0.042 $\mu\text{m}$	
9	Overlay FIA	$\leq 0.075\mu\text{m}$	X:   M   + 3 $\sigma$	0.027 $\mu\text{m}$	
		$\leq 0.075\mu\text{m}$	Y:   M   + 3 $\sigma$	0.045 $\mu\text{m}$	

# ILLUMINATION



# RETICLE ROTATION

## Reticle Rotation

Meas.Proc.Prog.: 226USRD.MSRR      Machine ID: \_\_\_\_\_  
 Condition File: 226RRD.SMCP      Date: 2019-09-06 15:47:31  
 Result File: 20190906\_RRD.MESR      Comment: Reticle rotation [ R2205HDIS ]

Align.	Block	Measured Value				
1	1	-0.037	-0.034	-0.031	-0.037	-0.038
	2	-0.036	-0.039	-0.034	-0.035	-0.036
	3	-0.034	-0.033	-0.035	-0.037	-0.038
	4	-0.036	-0.035	-0.039	-0.037	-0.033
	5	-0.039	-0.037	-0.034	-0.037	-0.038
2	1	-0.032	-0.034	-0.038	-0.039	-0.036
	2	-0.031	-0.040	-0.037	-0.038	-0.038
	3	-0.033	-0.037	-0.039	-0.034	-0.033
	4	-0.034	-0.034	-0.037	-0.039	-0.038
	5	-0.039	-0.037	-0.033	-0.036	-0.037
3	1	-0.038	-0.037	-0.030	-0.035	-0.033
	2	-0.038	-0.038	-0.035	-0.038	-0.038
	3	-0.037	-0.036	-0.039	-0.036	-0.037
	4	-0.038	-0.037	-0.033	-0.033	-0.037
	5	-0.036	-0.033	-0.033	-0.038	-0.035
4	1	-0.032	-0.034	-0.035	-0.033	-0.033
	2	-0.039	-0.039	-0.038	-0.036	-0.037
	3	-0.039	-0.039	-0.038	-0.034	-0.034
	4	-0.031	-0.039	-0.030	-0.036	-0.033
	5	-0.034	-0.037	-0.030	-0.036	-0.037
5	1	-0.034	-0.034	-0.039	-0.038	-0.037

Align.	Average
1	-0.036 [μm]
2	-0.036 [μm]
3	-0.036 [μm]
4	-0.035 [μm]
5	-0.035 [μm]
6	_____ [μm]
7	_____ [μm]
8	_____ [μm]
9	_____ [μm]
10	_____ [μm]

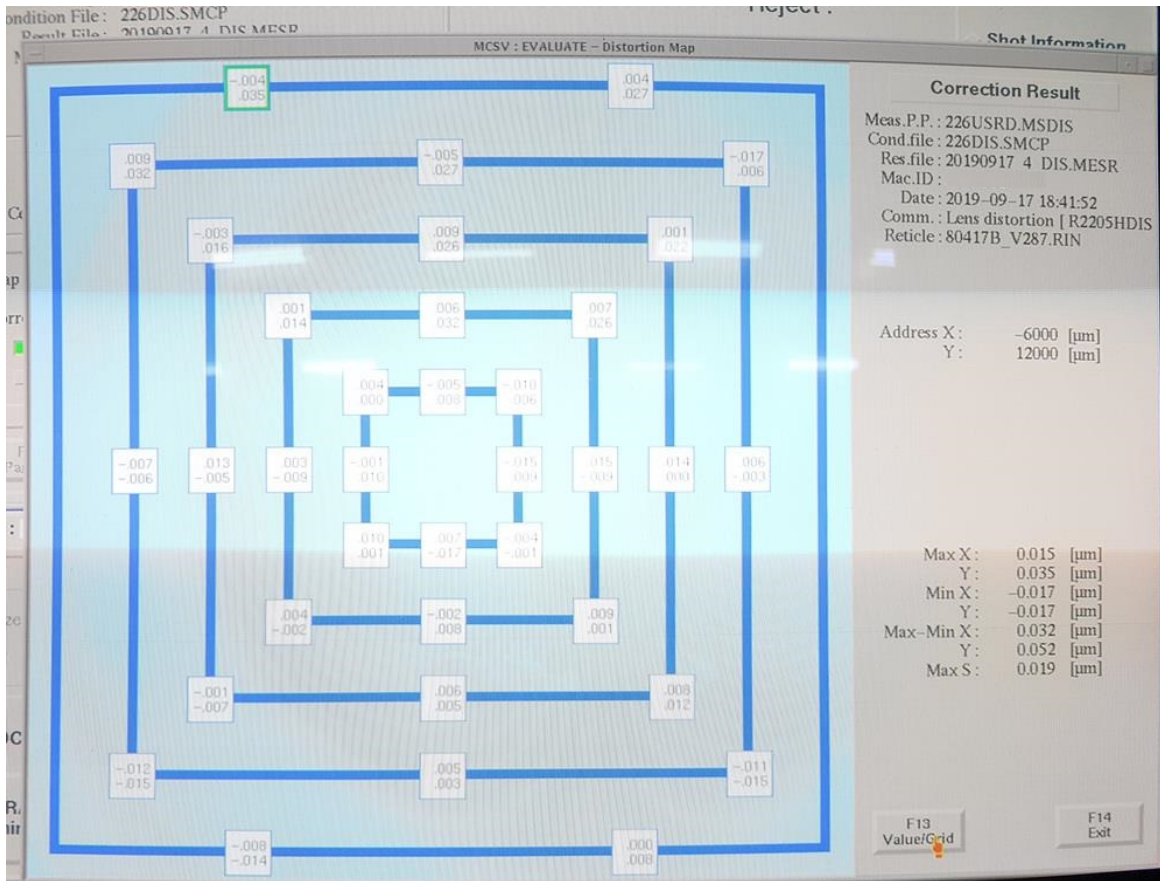
  

**Total**  
 Reticle Rotation : -0.018 [μm]  
                               : -1.787 [μrad]  
 Repeatability  
                               (3σ): 0.001 [μm]

**Each Wafer**  
 Reticle Rotation : -0.018 [μm]  
                               : -1.787 [μrad]  
 Repeatability  
                               (3σ): 0.001 [μm]

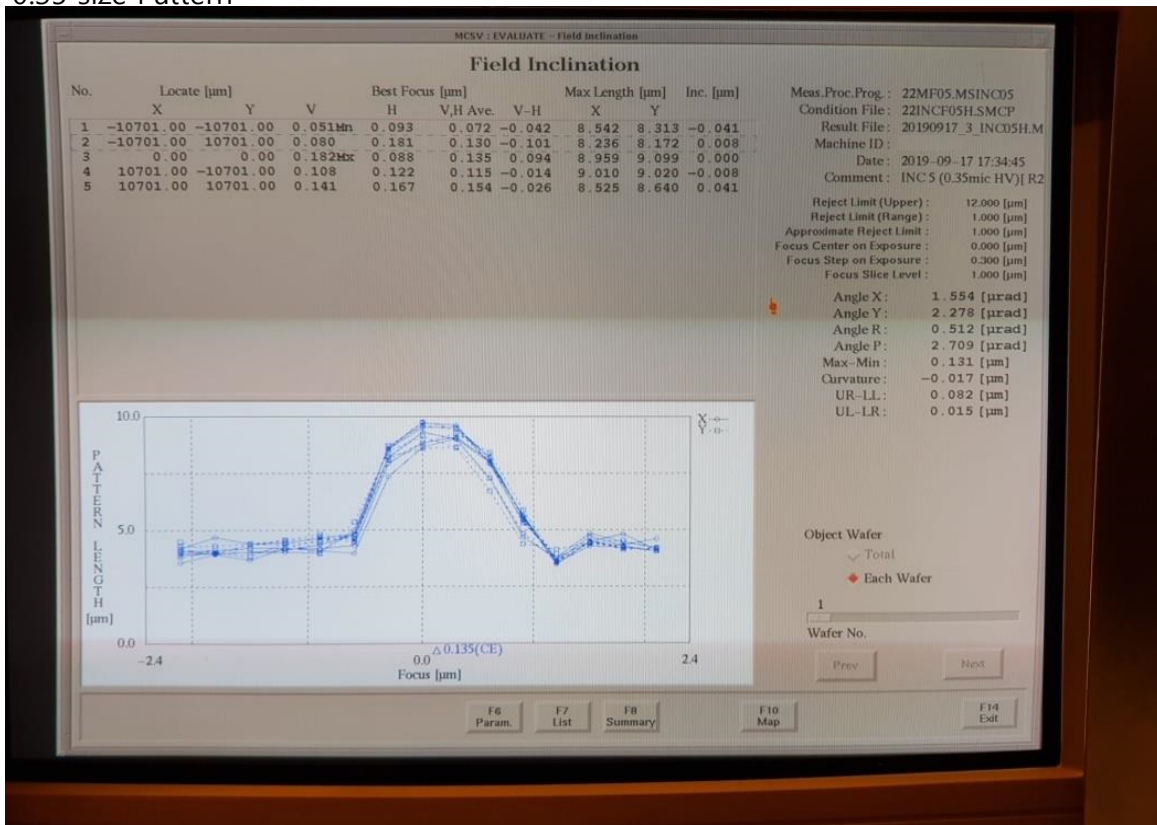
1  
 Wafer No. \_\_\_\_\_

# DISTORTION

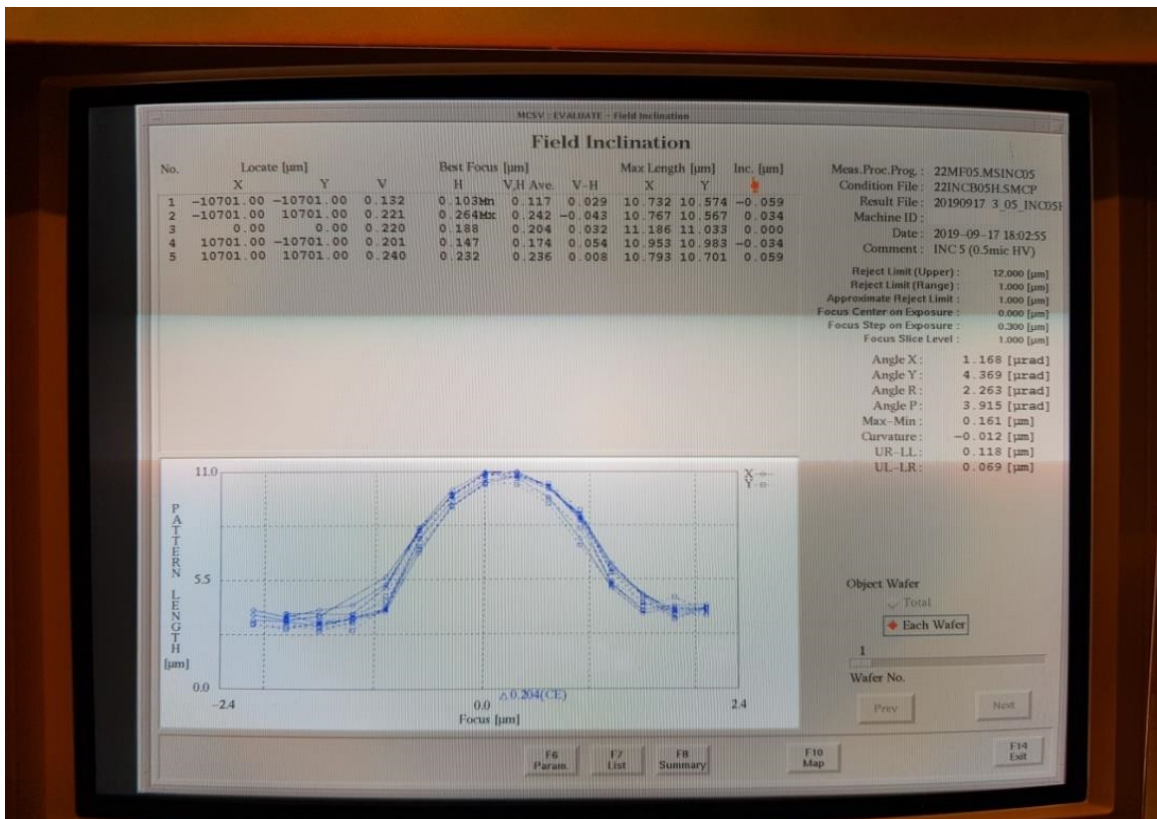


# INCLINATION

## 0.35 size Pattern

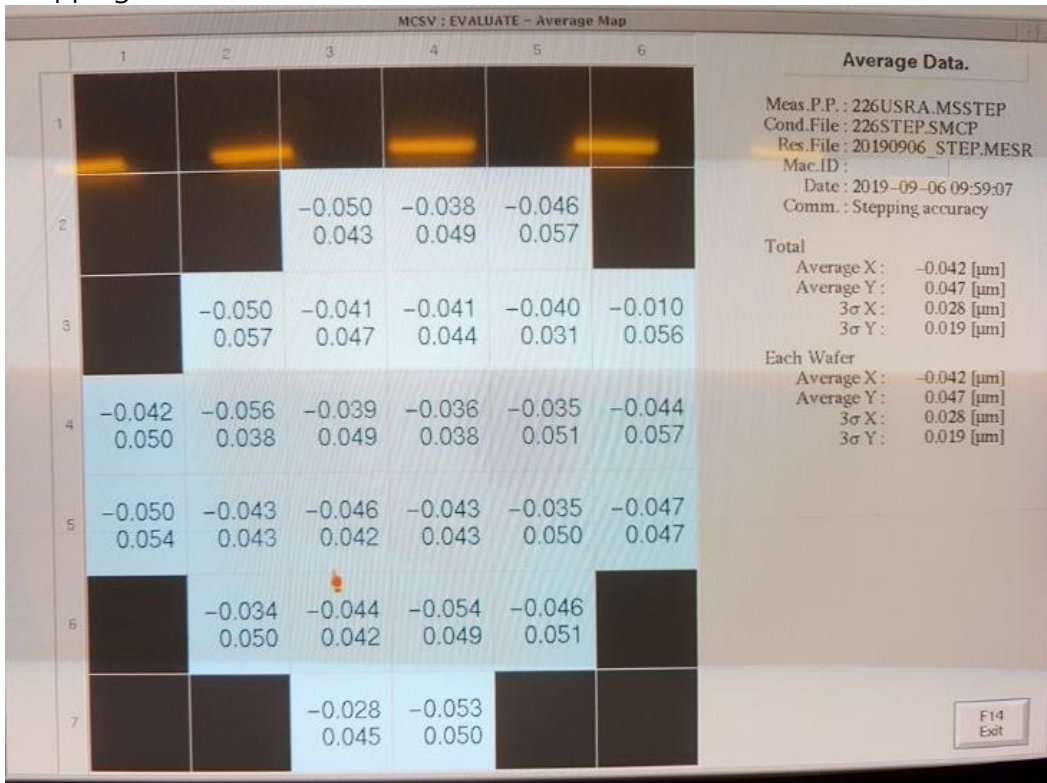


## 0.5 size Pattern

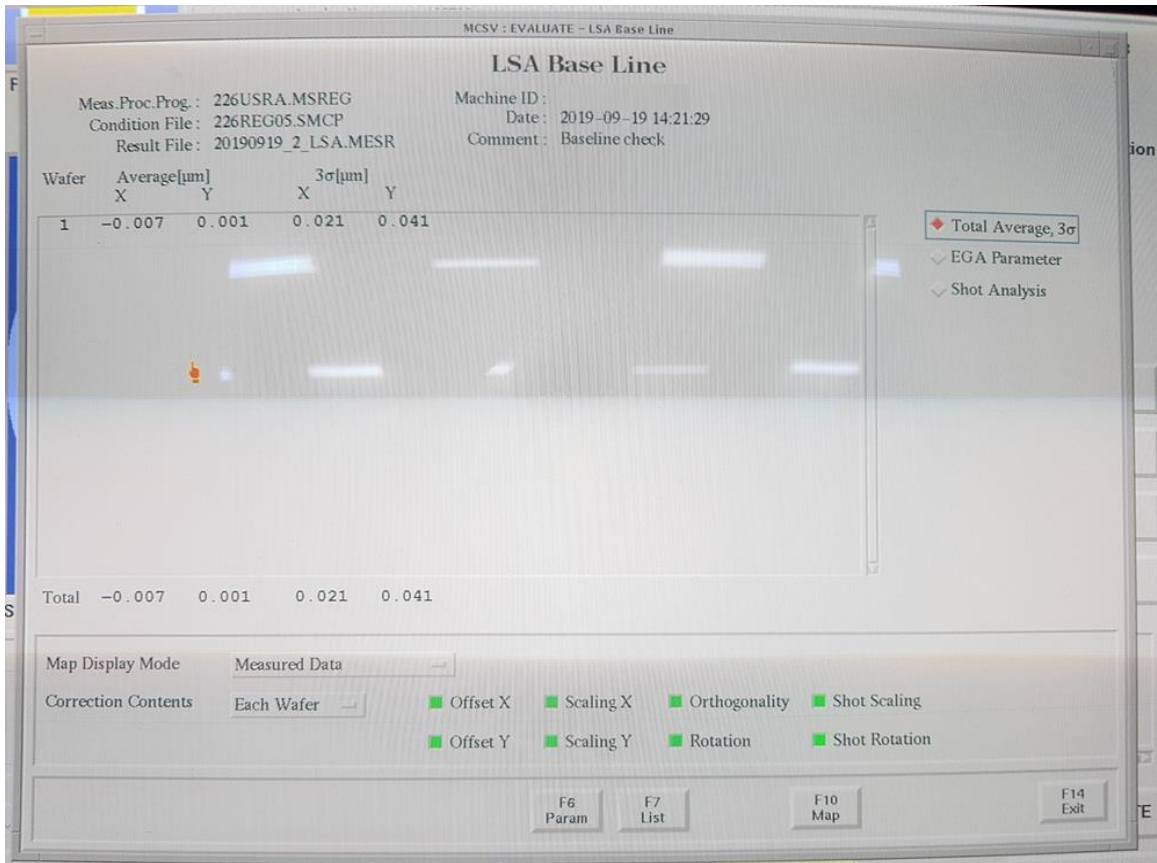




# Stepping



# OVERLAY\_LSA



# OVERLAY\_FIA

